

# Design Planning Trends And Challenges

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# **Agenda**



Design Planning: What and Why

**Design Trends** 

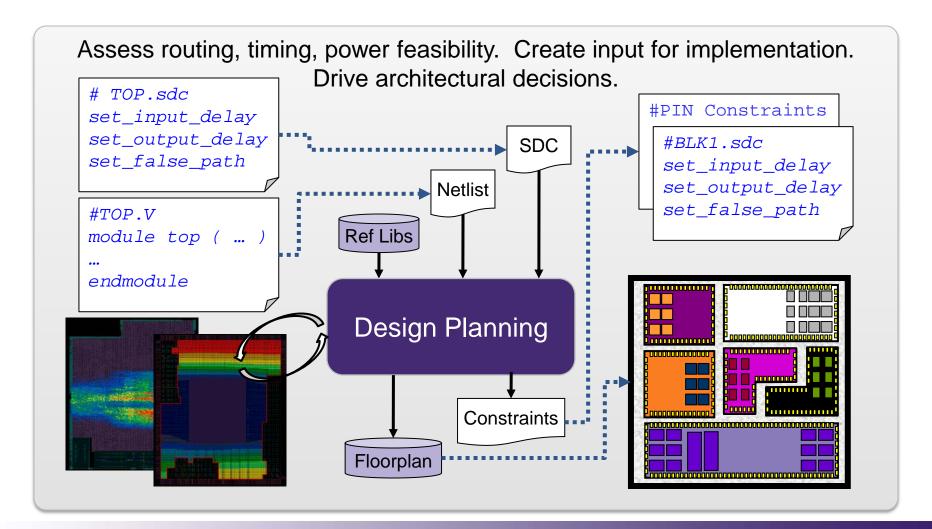
Design Planning Challenges

**New Trends** 

Discussion

# What Is Design Planning?

### A Process To Create Chip Floorplan And Constraints



# **Key Aspects Of Design Planning**

### For Flat And Hierarchical Methodologies

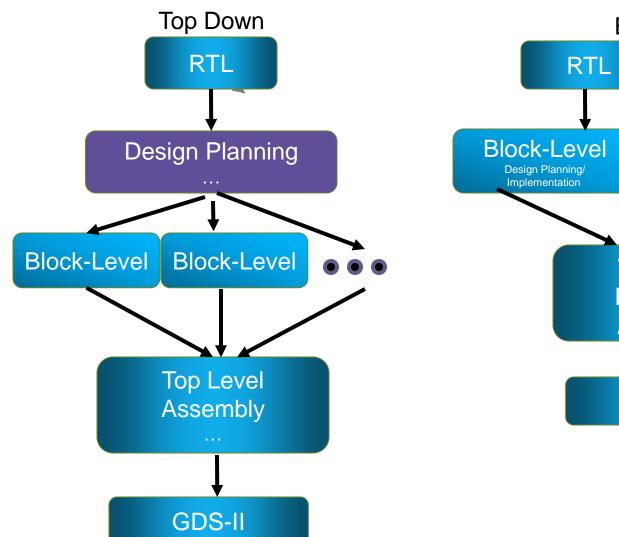
### Prototyping

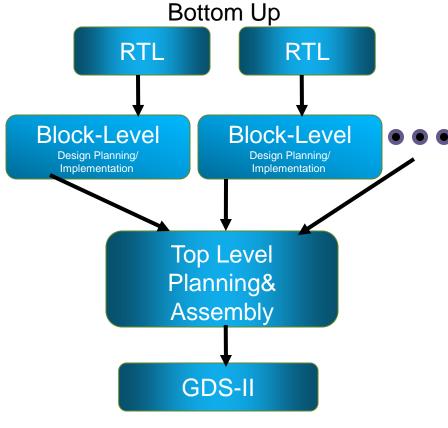
- Exploration of implementation strategies
- Identify and address gross implementation issues
- Feedback to RTL designs/synthesis
- Architectural exploration

### Detailed Planning

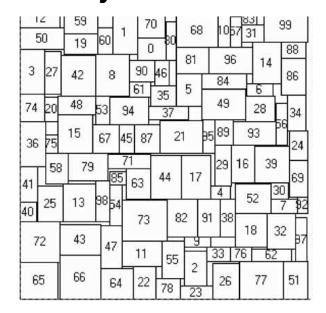
- Prepare best input/constraints for detailed implementation
- Maximize QoR and Minimize runtimes for implementation

# **Hierarchical Design Methodologies**





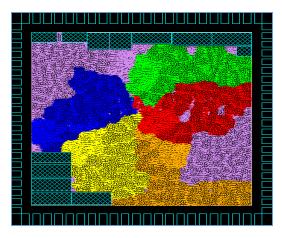
# Traditional Floorplanning Problem *Objective*



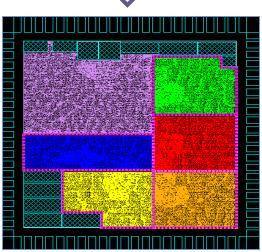
- Produce overlap free block placement
- Minimize
  - Area, Wirelength
  - White space
- Other considerations
  - Chip Area, Aspect ratio
  - IO PADs
  - Buss Driven

T-C Chen et. al., TCAD 2006 S.N. Adya et. al., ICCD 2001 H. Xiang et. al., ICCAD 2003

# Full Chip Virtual Flat Floorplanning







- Full netlist available
- Quick flat placement
  - Wirelength minimization
  - Congestion, timing
- Block placement, shapes
  - Cover standard cell, Macro areas

# **Agenda**

Design Planning: What and Why



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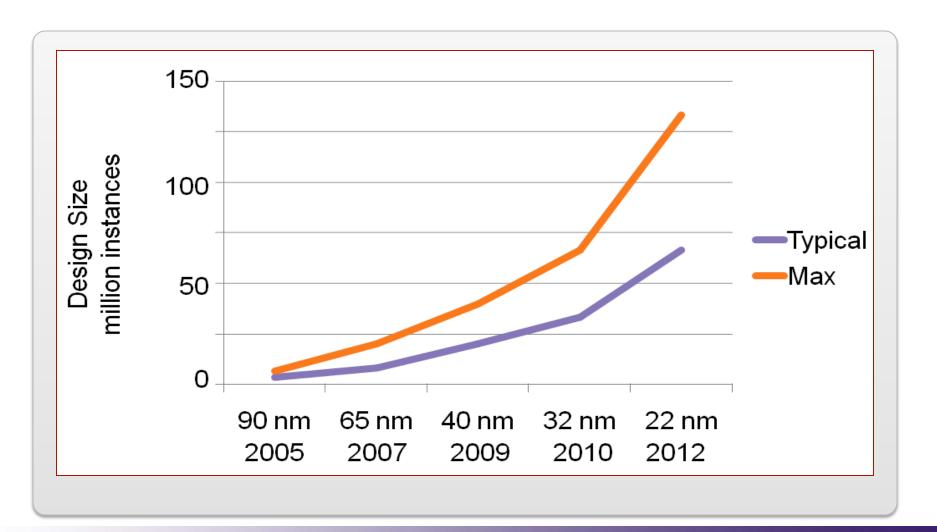
**Design Planning Complexities** 

**New Trends** 

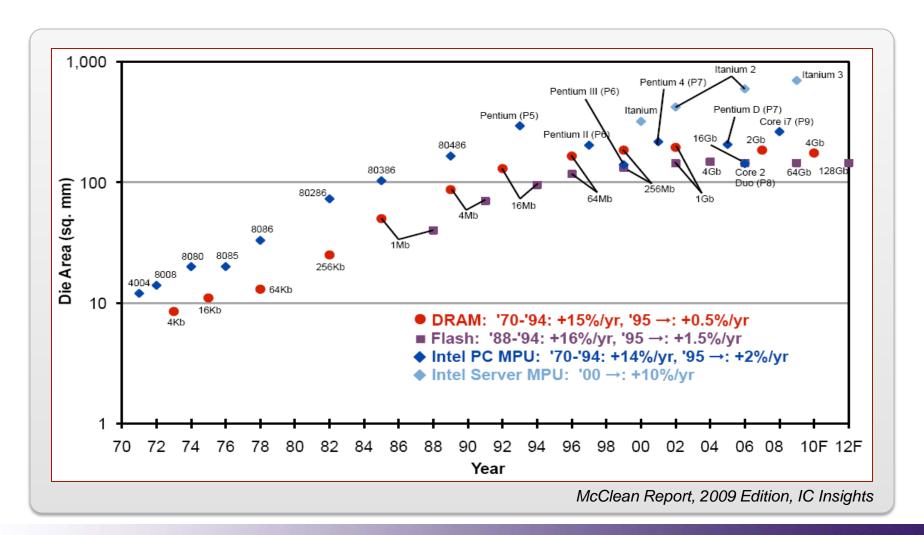
Discussion

# **Design Complexity Trends**

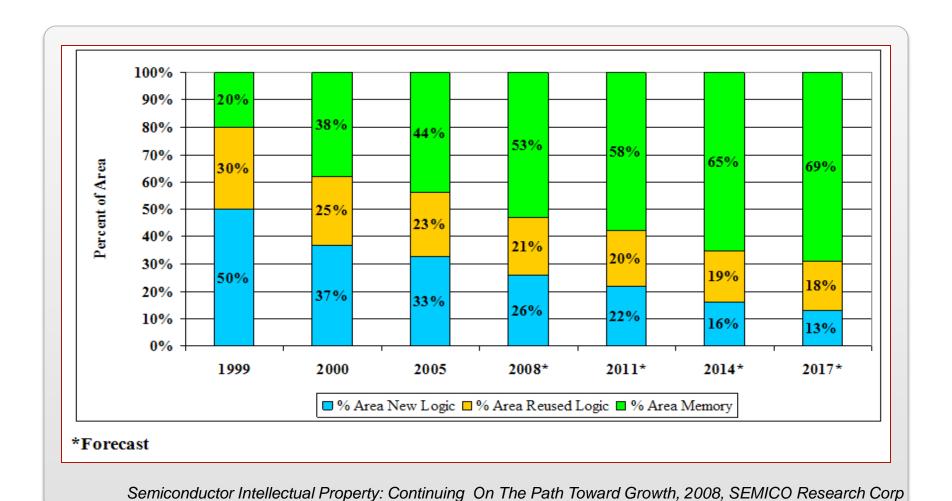
### Smaller Process Nodes Leading To Increased Design Size



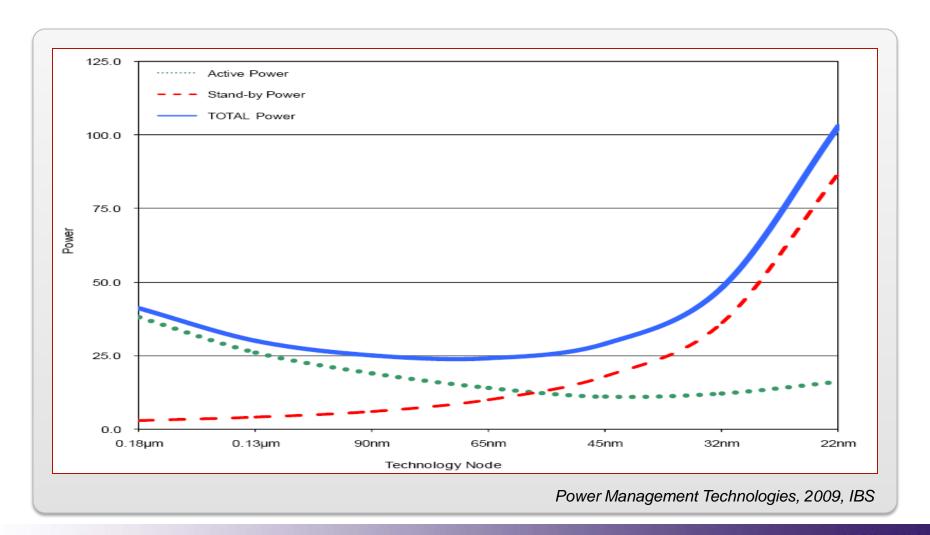
# **Chip Size Trends**



# Roadmap For Die Area Partitioning



### **Power Trends**



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Design Planning Challenges

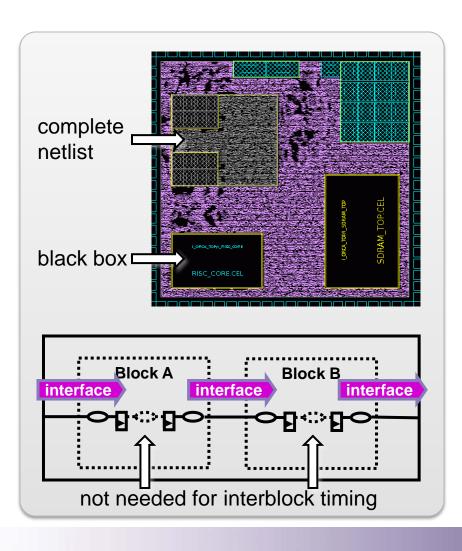
**New Trends** 

Discussion

# **Design Planning Challenges**

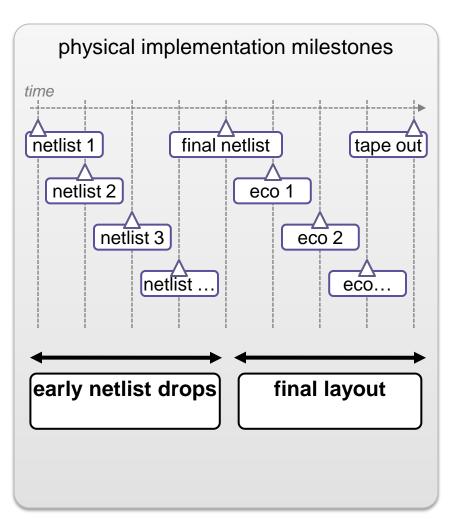
- Design sizes
- Evolving netlist and constraints
- Complex IO structures
- Large number of embedded macros
- Fast and accurate predictability
- Abutted and semi-abutted partitions
- Repeated blocks
- Low power challenges
- Clock planning

# **Increasing Design Sizes**



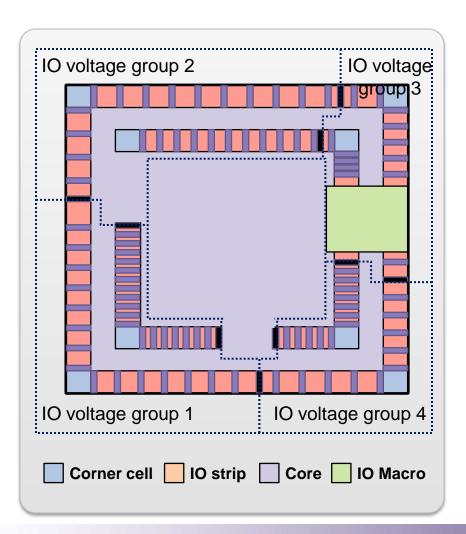
- Full-chip design planning
- Large netlists: 20-40M instances
  - Load essential data
  - Levels of abstraction
  - Partial netlist planning
- Large die sizes

# **Evolving Netlists And Constraints**



- Parallel RTL and physical design
- Constant netlist changes
- Incomplete netlist, libraries
- Inconsistent and mismatched data/netlist
- Incomplete constraints
- Missing clocks

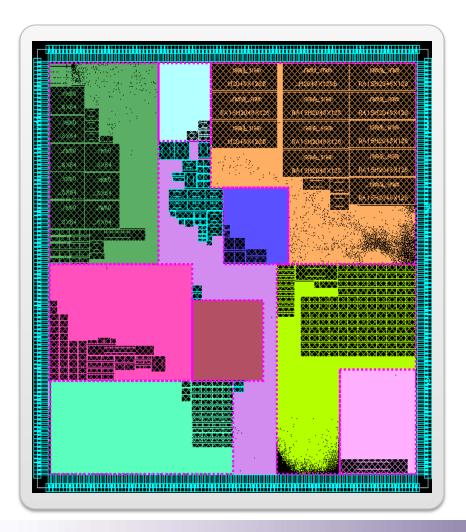
# **Complex IO Structures**



- Multi-ring IO PADs
- Multi-height IO PADs
- Mixed Macros and PADs
- Mixed IOs and pins
- Multi-VDD PADs
- Rectilinear boundaries

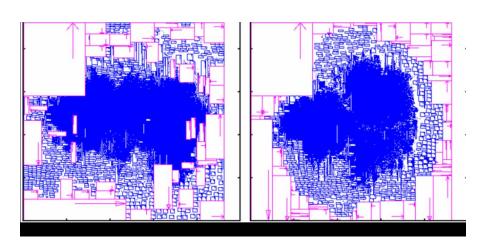
# Large Number Of Embedded Macros

### **Considerations**



- Large percentage of die area
- Varying sizes/shapes/rectilinear
- Place and route blockages
- Relative constraints
- Macro orientations
- Fragmented SC areas
- Channels

# Large Number Of Embedded Macros Objectives



MP-Tree based

Produce legal placement

Non overlapping macros

#### Minimize

- Wirelength, timing, congestion
- Displacement from initial placement

#### Maximize

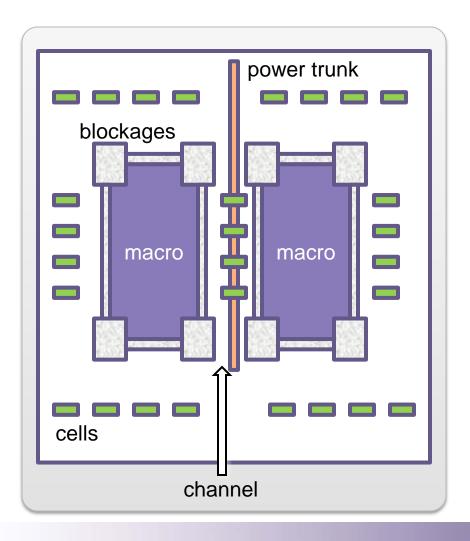
Contiguous routing areas

H-C, Chen et. al., ICCAD 2008 T-C Chen et. al., TCAD 20008 T. Gao, DAC 1992

TCG Based

# Large Number Of Embedded Macros

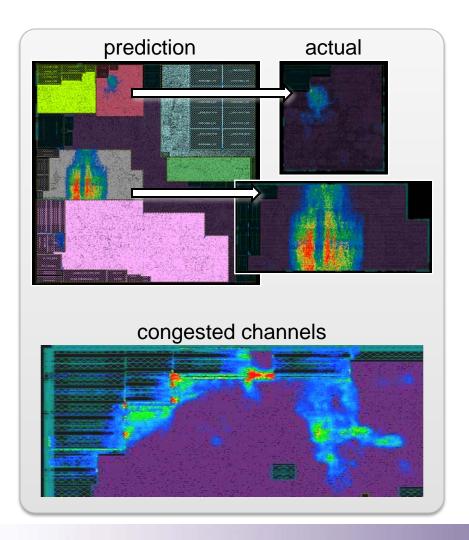
### Sub-problems



- Channel sizing
  - Routing estimation
  - Power for std. cells
- Blockage creation
  - Avoid edge and corner congestion

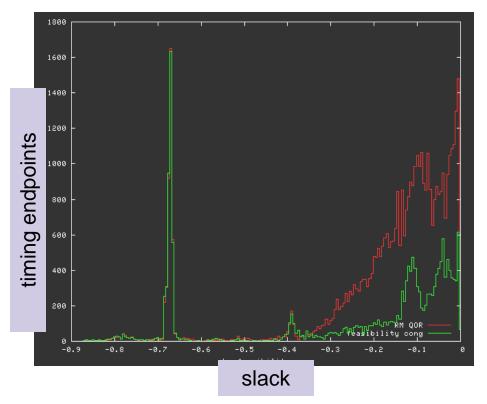
H-C, Chen et. al., ICCCAD 2008 T-C Chen et. al., TCAD 20008 T. Gao, DAC 1992

# **Fast and Accurate Predictability**



- Quick assessment of floorplan feasibility
- Routability
  - Fast congestion estimation
  - Dirty floorplans
- Channel and block congestion

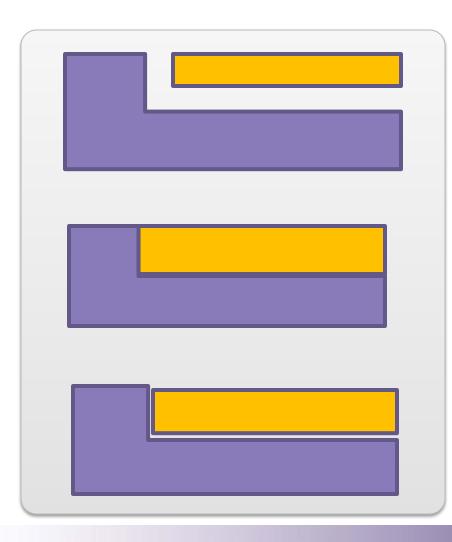
# **Fast and Accurate Predictability**



- Timing predictability
  - Virtual timing estimation
  - Quick buffering
  - Estimated timing models
  - Dirty constraints
- Area assessment
  - Estimated buffer count and cell area
  - Die area
  - Block area

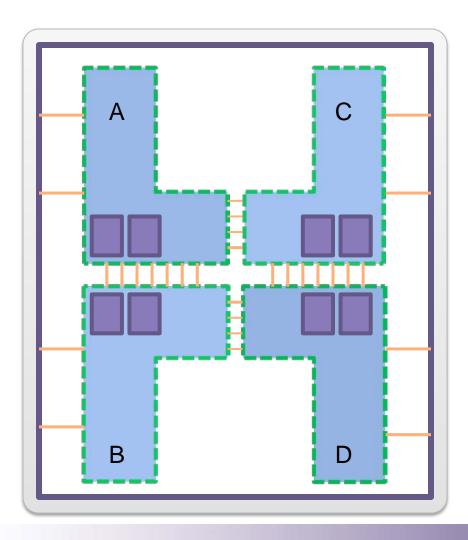
# **Hierarchical Designs**

### Channeled, Abutted, and Near Abutted



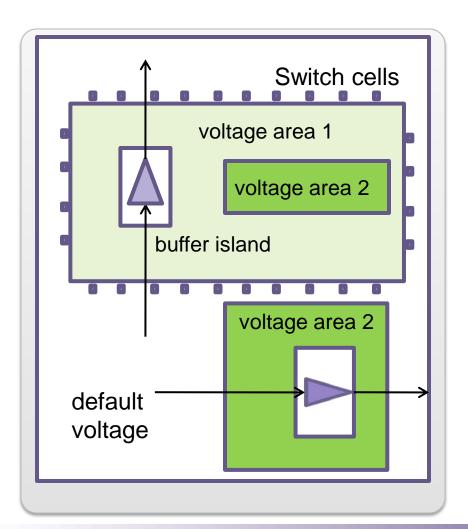
- Channeled (most common)
  - Top level logic and channels
  - Relatively simple to plan and to close top level
- Abutted (high end)
  - No top level logic and channels
  - Better die area
  - Needs robust interblock planning
  - Complex clock design
- Near abutted (gaining popularity)
  - No top level logic
  - Narrow channels for buffers, clocks
  - Good tradeoff between channeled and abutted

# Repeated Blocks



- Functionally identical blocks layed out identically
- Bottom up design
  - Simple, sub-optimal
- Top down in-context design
  - Automatic identical shapes, pins, constraints
  - Rotations, mirroring

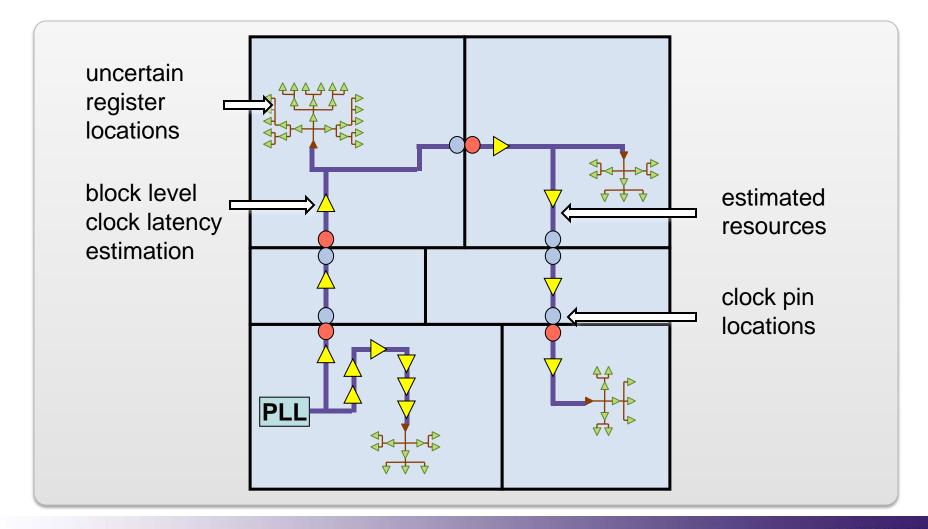
# **Low Power Planning**



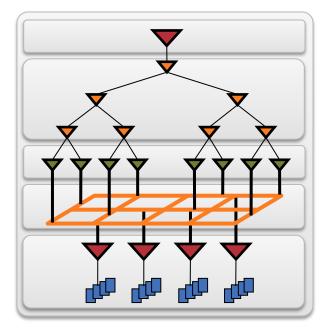
- Power domains/voltage areas
  - Physical locations/shapes
  - Congestion/timing
- Shutdown regions
  - Switch cell planning
    - Area/Power/performance tradeoff
  - Turn-on sequence
- Buffer islands in voltage areas

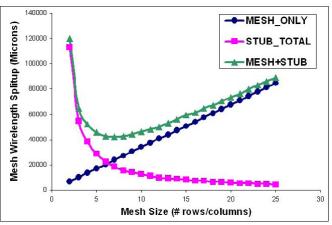
H-S Won et. al., ISLPED 2003 C-Y Yeh et. al., SOCC 2007

# Clock Planning Top Level Clock Tree



# **Clock Mesh Planning**





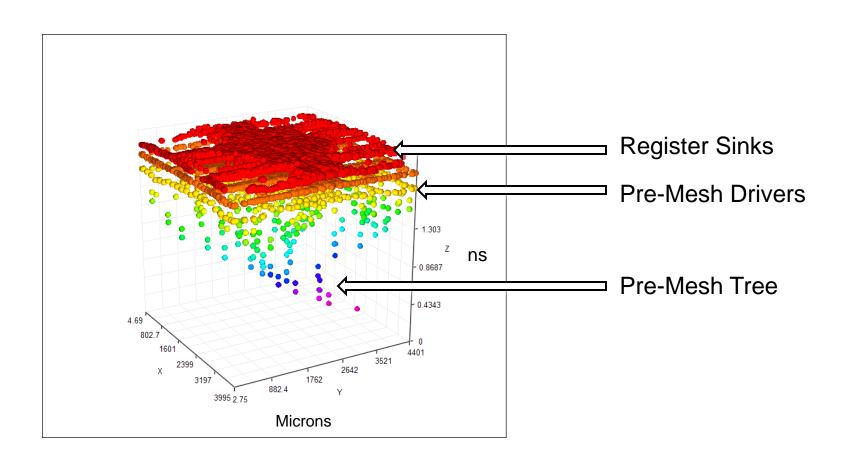
### Plan mesh

- Skew constraint
- Minimize Mesh size + stub/twig routes
- Layers
- Mesh drivers
  - Number, size, location
- Mesh Analysis
  - Multi-driver analysis

A. Rajaram et. al., DAC 2008.



### 3D Visualization of Clock Mesh Simulation



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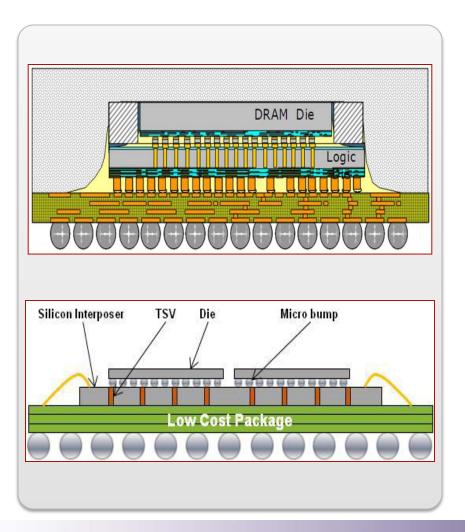
Discussion

### **New Trends**

- 3D chip planning
- Multi-level hierarchical planning
  - For increasing design sizes
- Design Planning and Logic Synthesis

# 3D Chip Design Planning

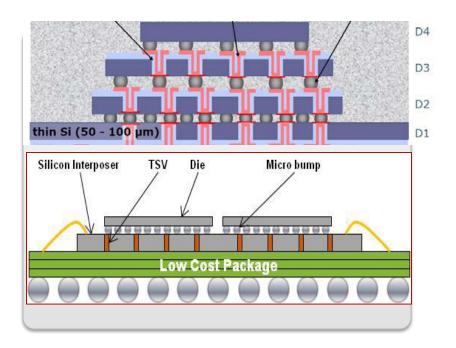
### **Objectives**



- Overlap-free placement of the design blocks
- Minimize wirelength (performance)
  - 3D within and between blocks
- Minimize power
  - Reduce IOs or use weaker ones
  - Minimize wirelength
  - Design each layer in its optimal technology node
- Minimize area

# 3D Chip Design Planning

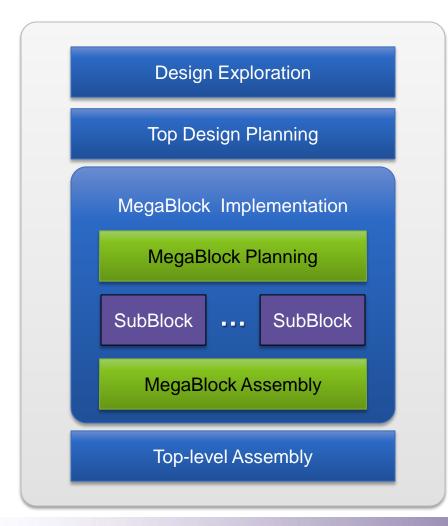
### **Sub-problems**

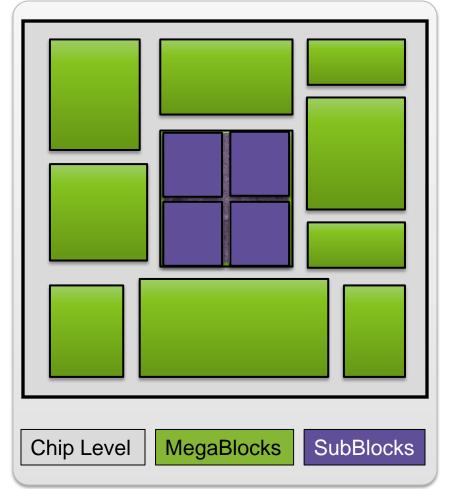


- Multi-die partitioning and floorplanning
  - Timing, power density
  - Through-silicon via planning
    - Optimal through silicon via assignments
    - Through-Si VIA and pin assignment
  - 3D visualization

S.Fujita et al. "Perspectives and Issues in 3D-IC from Designer's Point of View", IEEE International Symposium on Circuits and Systems, 2009. Xu He, et. al., SLIP 2009.

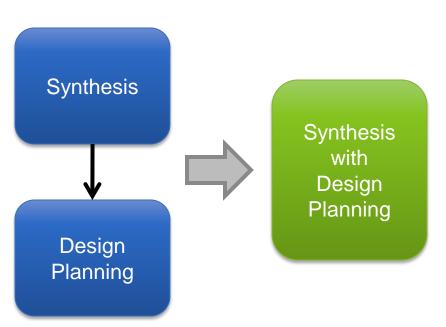
### Multi-Level Hierarchical Design





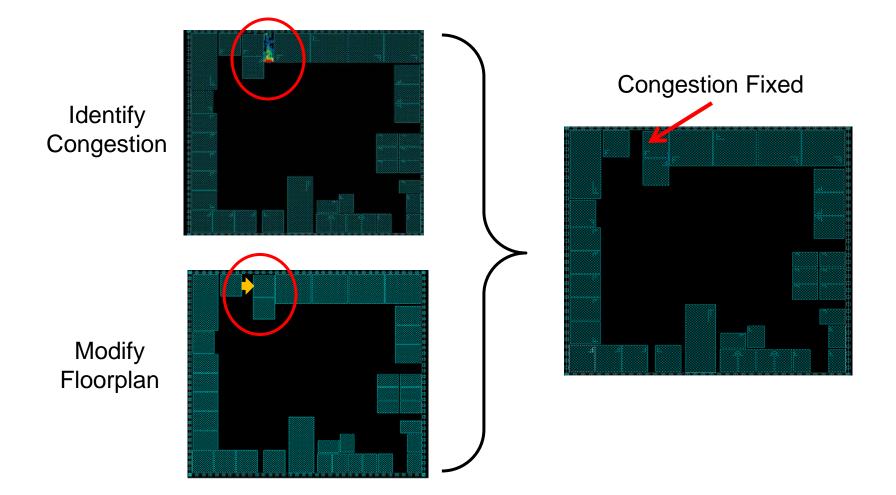


# **Design Planning and Logic Synthesis**



- Floorplanning and logic synthesis impact each other
- Solving timing/congestion problems need synthesis and floorplanning solutions
- Enabling architectural decisions
- There is a need to bring logic synthesis and design planning closer

# **Design Planning and Logic Synthesis**



### **Discussion**

- Bringing design planning earlier into design flows is key to productivity and convergence
  - RTL design and synthesis with design planning
  - Handling evolving designs, constraints
- Traditional design planning to deal with emerging complexities in low power, design size, 3D chips.

# Acknowledgements

- Jamil Kawa, Group Director R&D, Synopsys Inc.
- Dwight Hill, Principal Engineer, Synopsys Inc.
- Steve Kister, TMM, Synopsys Inc.